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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/713,777	NAKAGAWA ET AL.	
Examiner	Art Unit	
Ari M. Diacou	3663	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH   (INCLUDING SEAR	NOTES CH STRATEG\	<b>(</b> )
	DATE	EXMR
See attached EAST report	8/7/2006	AMD
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